

Special Issue

Sensing and Imaging for Defect Detection

Message from the Guest Editors

This Special Issue calls for papers aimed at the detection of the most common defects, including surface defects, subsurface defects and so on. Recent advances in sensor technologies form the basis of the development of nondestructive testing technology, data acquirement processing, and image processing technology. The editors welcome the submission of high-quality research papers not previously published in other journals as well as review articles discussing recent advancements in the development of sensing and imaging techniques for defect detection technology that can be easily used in the NDT&E field. Keywords:

- sensors NDT&E technology
- defect detection technology
- imaging technology
- data acquirement and processing
- sensing techniques

Guest Editors

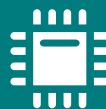
Prof. Dr. Haitao Wang

Dr. Yongkai Zhu

Dr. Fei Fei

Deadline for manuscript submissions

closed (20 September 2024)



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About the Journal

Message from the Editor-in-Chief

Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. *Sensors* organizes Special Issues devoted to specific sensing areas and applications each year.

Editor-in-Chief

Prof. Dr. Vittorio M. N. Passaro

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